



EXICOR GEN SERIES

Ultra-low retardation measurements.
Award Winning.
Reliable.

Applications

- ◆ Quality control metrology
- ◆ Low-level birefringence measurements of
 - ◆ Display glass
 - ◆ LCD
 - ◆ Large irregular shaped planar glass and plastic
 - ◆ Plastic film

System Options

- ◆ Scan In Motion (SIM)
- ◆ Keep Out Barrier
- ◆ Manual or Auto Tilt Stage
- ◆ Thickness and Warpage Sensors on GEN5 or GEN6

Significant Features

- ◆ Unprecedented sensitivity in low-level birefringence measurement
- ◆ Simultaneous measurement of birefringence magnitude and angle
- ◆ Precision repeatability
- ◆ High-speed measurement
- ◆ No moving parts in the optical system
- ◆ Automatic mapping of variable-sized optical elements
- ◆ Photoelastic modulator technology
- ◆ Simple, user-friendly operation



GEN system with tilt option



GEN6 TW



GEN5

GEN Specifications

	GEN5	GEN6	GEN9
Retardation Range		0.005nm to 300 nm	
Resolution ¹		0.001 nm	
Repeatability ¹		±0.01 nm (Retardation < 1 nm) or ± 1% (Retardation > 1 nm)	
Angular Resolution/Repeatability ¹		0.01° / ± 0.05°	
Measurement Time ²		Up to 10 pps	
Wavelength ³		632.8 nm	
Spot size		~ 1 mm typical	
Demodulation Analysis Technique		Hinds Instruments Signaloc™ Lock-in Amplifiers	
Measurement Units		nm (retardation), ° (angle)	
Maximum Sample Size (mm)	1175 x 1375	1600 x 2000	2500 x 3000
Maximum Scan Area (mm)	1100 x 1300	1575 x 1925	2400 x 2800

¹ Typical performance at 5nm Retardation

² Maximum data collection speed. Sample XY scan time dependent on stage movement parameters.

³ Custom wavelengths available

GEN System Glass Measurements

GENERATION	GLASS SIZE
5	1100 x 1250
	1100 x 1300
5.5	1300 x 1500
	1500 x 1850
8	2160 x 2450
	2200 x 2500
9	2400 x 2800
10	2580 x 3050
	3000 x 3200

